

<b>Notice of References Cited</b>	Application/Control No. 10/550,902		Applicant(s)/Patent Under Reexamination OHYA ET AL.	
	Examiner Patricia L. Hailey		Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,071,517	12-1991	Oabayashi, Kiyoshi	205/158
*	C	US-2002/0132159	09-2002	Ohya et al.	429/44
*	D	US-5,707,755	01-1998	Grot, Stephen Andreas	429/40
*	E	US-6,156,449	12-2000	Zuber et al.	429/42
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Epitaxially grown model catalyst particles of platinum, rhodium, iridium, palladium and rhenium studied by electron microscopy," G. Rupprechter et al. Thin Solid Films (1995), pages 148-155.
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	W	"Electron diffraction and HRTEM studies of multiply-twinned structures and dynamical events in metal nanoparticles: facts and artefacts," P. A. Buffat. Materials Chemistry and Physics 81 (2003), pages 368-375
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

*PL Hailey*